Application/Control No. Applicant(s)/Patent Under Reexamination 10/564,771 CHO ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Ajith Jacob 2169 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY * US-2003/0108205 A1 06-2003 Joyner et al. 380/277 * US-6,580,756 B1 06-2003 Matsui et al. 375/240.08 В US-С US-D US-Ε US-F US-G US-Н US-US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY N 0 Ρ Q R s Ŧ **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) Ú ٧ W Х

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